

Notice of References Cited	Application/Control No. 10/555,898		Applicant(s)/Patent Under Reexamination OCHI ET AL.	
	Examiner Jason A. Sese		Art Unit 4174	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0176046 A1	11-2002	Kitamura et al.	349/153
*	B	US-2006/0006362 A1	01-2006	Miyawaki et al.	252/299.01
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	K	US-			
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	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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